





# Annex I

## No. 4V241202.BTEW061

1. SC 3 (SIL 3 Capability):  
The product has met the manufacturer design process requirements of safety integrity level (SIL) 3. These are intended to achieve sufficient integrity against systematic errors of design by the manufacturer.
2. A Safety Instrumented Function (SIF) designed with this product must not be used at a SIL level higher than stated.
3. Random Capability:  
The SIL imposed by the Architectural Constraints must be met for each element.
4. IEC 61508 Failure Rates in FIT\*

Device	$\lambda_{SD}$	$\lambda_{SU}$	$\lambda_{DD}$	$\lambda_{DU}$	SFF
GD	0	39	801	53	94.0%
CHR	0	34	757	48	94.3%

\*FIT = 1 failure/10<sup>9</sup> hours

5. The Safety Integrity Level (SIL) of an entire Safety Instrumented Function (SIF) must be verified via a calculation of  $PFD_{AVG}$  considering redundant architectures, proof test interval, proof test effectiveness, any automatic diagnostics, average repair time and the specific failure rates of all products included in the SIF. Each subsystem must be checked to assure compliance with minimum hardware fault tolerance (HFT) requirements.